

60V N-Channel Enhancement Mode MOSFET

Description

The AP50N06Y uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS}=60V I_D =50A

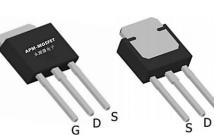
 $R_{DS(ON)} < 20m\Omega @ V_{GS}=10V$ (Type: 14m Ω)

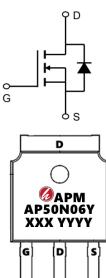
Application

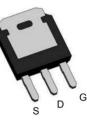
Battery protection

Load switch

Uninterruptible power supply







Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|------------|--------------------|----------|
| AP50N06Y | TO-251L-3L | AP50N06Y XXXX YYYY | 4000 |
| AP50N06Y | TO-251S-3L | AP50N06Y XXXX YYYY | 4000 |

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Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

| Symbol | Parameter | Parameter Rating | |
|-------------------------------------|--|-------------------------|------|
| VDS | Drain-Source Voltage | Drain-Source Voltage 60 | |
| VGS | Gate-Source Voltage | ±20 | V |
| I₀@Tc=25℃ | $_{C=25^{\circ}C}$ Continuous Drain Current, V _{GS} @ 10V ¹ 50 | | А |
| I₀@Tc=100°C | Continuous Drain Current, V _{GS} @ 10V ¹ | 25 | A |
| IDM | Pulsed Drain Current ² | 90 | А |
| EAS | Single Pulse Avalanche Energy ³ | 39.2 | mJ |
| IAS | Avalanche Current | 28 | А |
| P _D @T _C =25℃ | Total Power Dissipation ⁴ | 45 | W |
| PD@TA=25°C | Total Power Dissipation ⁴ | 2 | W |
| TSTG | Storage Temperature Range | -55 to 150 | °C |
| TJ | Operating Junction Temperature Range | -55 to 150 | °C |
| R₀JA | Thermal Resistance Junction-Ambient ¹ | 62 | °C/W |
| R₀JC | Thermal Resistance Junction-Case ¹ | 2.8 | °C/W |

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

| Symbol | Parameter | Conditions | Min. | Тур. | Max. | Unit | |
|------------------------------------|--|--|------|-------|------|-------|--|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V , I _D =250uA | 60 | 65 | | V | |
| ∆BVDSS/∆TJ | BV _{DSS} Temperature Coefficient | Reference to 25°C , I _D =1mA | | 0.057 | | V/°C | |
| | | V _{GS} =10V , I _D =20A | | 14 | 20 | | |
| RDS(ON) | Static Drain-Source On-Resistance ² | V _{GS} =4.5V , I _D =10A | | 18 | 25 | mΩ | |
| VGS(th) | Gate Threshold Voltage | | 1.2 | 1.8 | 2.5 | V | |
| $\bigtriangleup V_{\text{GS(th)}}$ | V _{GS(th)} Temperature Coefficient | V _{GS} =V _{DS} , I _D =250uA | | -5.68 | | mV/°C | |
| | Drain Course Lookana Current | V _{DS} =48V , V _{GS} =0V , T _J =25°C | | | 1 | uA | |
| IDSS | Drain-Source Leakage Current | V _{DS} =48V , V _{GS} =0V , T _J =55°C | | | 5 | | |
| IGSS | Gate-Source Leakage Current | V_{GS} =±20V , V_{DS} =0V | | | ±100 | nA | |
| gfs | Forward Transconductance | V _{DS} =5V , I _D =15A | | 45 | | S | |
| Rg | Gate Resistance | V _{DS} =0V , V _{GS} =0V , f=1MHz | | 1.7 | | Ω | |
| Qg | Total Gate Charge (4.5V) | | | 19.3 | | nC | |
| Q _{gs} | Gate-Source Charge | $V_{\text{DS}}\text{=}48V$, $V_{\text{GS}}\text{=}4.5V$, $I_{\text{D}}\text{=}15A$ | | 7.1 | | | |
| Q_gd | Gate-Drain Charge | | | 7.6 | | | |
| Td(on) | Turn-On Delay Time | | | 7.2 | | | |
| Tr | Rise Time | V _{DD} =30V , V _{GS} =10V , R _G =3.3□, | | 50 | | ns | |
| Td(off) | Turn-Off Delay Time | I _D =15A | | 36.4 | | 115 | |
| T _f | Fall Time | | | 7.6 | | | |
| Ciss | Input Capacitance | | | 2423 | | | |
| Coss | Output Capacitance | V _{DS} =15V , V _{GS} =0V , f=1MHz | | 145 | | pF | |
| Crss | Reverse Transfer Capacitance | | | 97 | | 1 | |
| ls | Continuous Source Current ^{1,5} | | | | 35 | Α | |
| ISM | Pulsed Source Current ^{2,5} | $V_G=V_D=0V$, Force Current | | | 80 | Α | |
| VSD | Diode Forward Voltage ² | V _{GS} =0V , Is=A , Tյ=25℃ | | | 1 | V | |
| t _{rr} | Reverse Recovery Time | | | 16.3 | | nS | |
| Qrr | Reverse Recovery Charge | IF=15A,dI/dt=100A/µs ,Tյ=25℃ | | 11 | | nC | |

Note :

1、 he data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.

 $2\,{\scriptstyle \smallsetminus}\,$ he data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%$

3、he EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=28A

4、 he power dissipation is limited by 150°C junction temperature

 5_{v} he data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

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Typical Characteristics

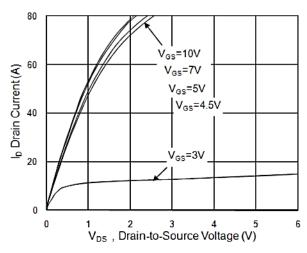


Fig.1 Typical Output Characteristics

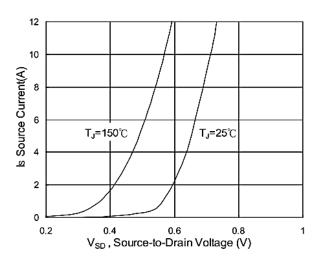


Fig.3 Forward Characteristics of Reverse

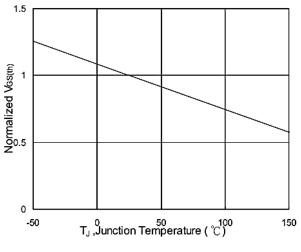


Fig.5 Normalized V_{GS} v.s T_J

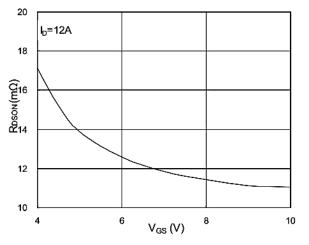


Fig.2 On-Resistance v.s Gate-Source

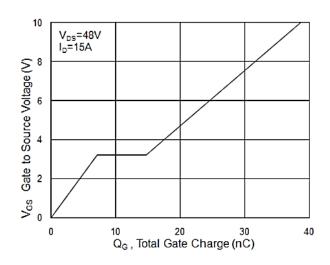


Fig.4 Gate-Charge Characteristics

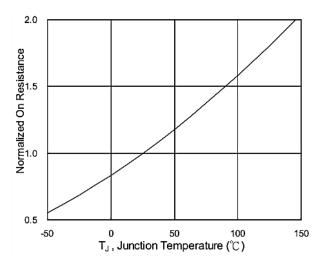


Fig.6 Normalized R_{DSON} v.s T_J



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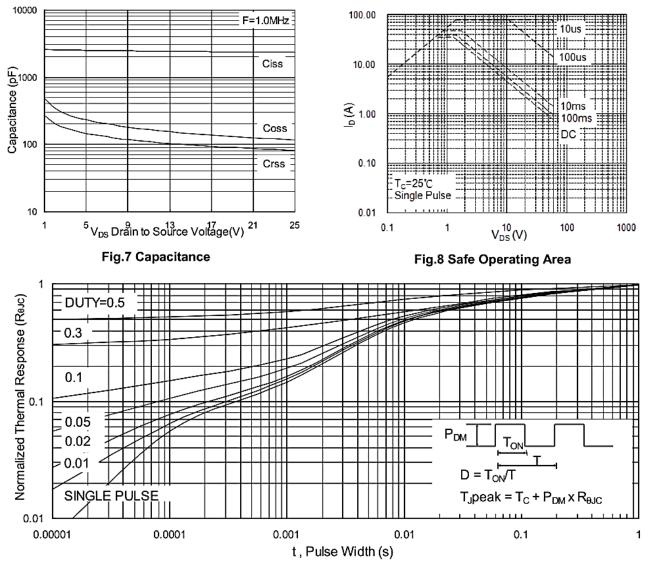


Fig.9 Normalized Maximum Transient Thermal Impedance

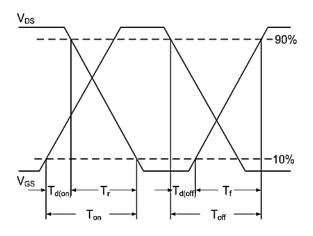


Fig.10 Switching Time Waveform

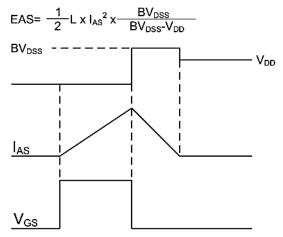


Fig.11 Unclamped Inductive Switching Waveform



AP50N06Y

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Package Mechanical Data-TO-251L-3L

TO-251

| | Dimensions | | | | | |
|------|-------------|------|------|--------|-------|-------|
| Ref. | Millimeters | | | Inches | | |
| | Min. | Тур. | Max. | Min. | Тур. | Max |
| A | 2.20 | | 2.40 | 0.086 | | 0.095 |
| A2 | 0.90 | | 1.20 | 0.035 | | 0.047 |
| в | 0.55 | | 0.65 | 0.022 | | 0.026 |
| B2 | 5.10 | | 5.40 | 0.200 | | 0.213 |
| B3 | 0.76 | | 0.85 | 0.030 | | 0.033 |
| С | 0.45 | | 0.62 | 0.018 | | 0.024 |
| C2 | 0.48 | | 0.62 | 0.019 | | 0.024 |
| D | 6.00 | | 6.20 | 0.236 | | 0.244 |
| E | 6.40 | | 6.70 | 0.252 | | 0.264 |
| G | | 2.30 | | | 0.091 | |
| н | 16.0 | | 17.0 | 0.630 |] | 0.669 |
| L | 8.90 | | 9.40 | 0.350 | | 0.370 |
| L1 | 1.80 | | 1.90 | 0.071 | | 0.075 |
| L2 | 1.37 | | 1.50 | 0.054 | | 0.059 |
| V1 | | 4° | 1 | | 4° | |

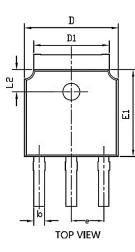
Package Information -TO-251

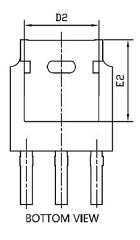
| OUTLINE | TUBE | INNER BOX | PER CARTON |
|---------|-------|-----------|------------|
| | (PCS) | (PCS) | (PCS) |
| TUBE | 80 | 4,000 | 32,000 |

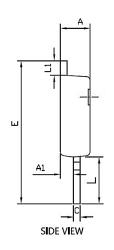


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Package Mechanical Data-TO-251S-3L







| | Common | | | | |
|--------|----------|------|------|--|--|
| Symbol | mm | | | | |
| | Mim | Nom | Max | | |
| A | 2.2 | 2.3 | 2.4 | | |
| A1 | 0.9 | 1.0 | 1.1 | | |
| b | 0.66 | 0.76 | 0.86 | | |
| С | 0.46 | 0.52 | 0.58 | | |
| D | 6.50 | 6.6 | 6.7 | | |
| D1 | 5.15 | 5.3 | 5.45 | | |
| D2 | 4.6 | 4.8 | 4.95 | | |
| E | 10.4 | | 11.5 | | |
| E1 | 6.0 | 6.1 | 6.2 | | |
| E2 | 5.400REF | | | | |
| е | 2.286BSC | | | | |
| L | 3.5 | 4.0 | 4.3 | | |
| L1 | 0.9 | | 1.27 | | |
| L2 | 1.4 | | 1.9 | | |

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| Edition | Date | Change |
|---------|-----------|-----------------|
| Rve1.0 | 2020/1/31 | Initial release |
| Rve1.1 | 2021/8/35 | New profile |

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